

Notice of References Cited

Application/Control No.

10/824,161

Applicant(s)/Patent Under
Reexamination
KONERSMANN ET AL.

Examiner

David Y. Jung

Art Unit

2134

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	U	http://msdn.microsoft.com/msdnmag/issues/03/07/DesignPatterns/
	V	http://tools.ietf.org/id/draft-ietf-sip-session-timer-10.txt
	W	http://tools.ietf.org/html/draft-ietf-sip-rfc2543bis-09 , section 26
	X	(http://www.microsoft.com/presspass/exec/flessner/04-11flessnerteched.msp)

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